#### STATUTORY DECLARATION

I, Takahiko NAKAZAWA, of Taiyo Seimei Otsuka Building 3F, 2-25-1, Kitaotsuka, Toshimaku, Tokyo, 170-0004, Japan, do solemnly and sincerely declare as follows:

I am well acquainted with the English and Japanese languages.

The attached translation is true into the English language of the accompanying certified copy of the document filed in the name of Fuji Photo Film Co., Ltd., in the Japanese Patent Office on 11 September 2003, in respect to an application for Patent.

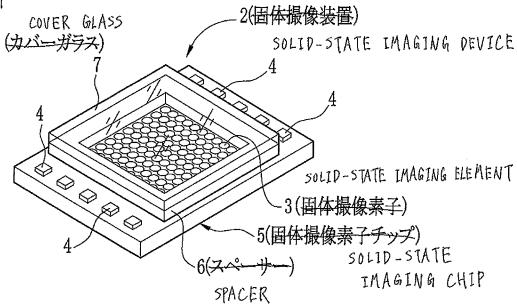
This 24th day of June 2009,

Takahiko NAKAZAWA

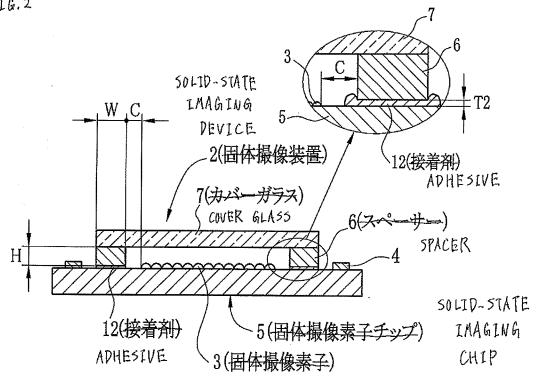
Jahahiko hakazawa

【書類名】図面 DRAWINGS 图上

FIG.1



### 图2



SOLID-STATE IMAGING ELEMENT

6(スペーサー)

SPACER



GLASS SUBSTRATE 10(ガラス基板)

12(接着剤) 6(スペーサー) ADHESIVE SPACER

# 图6]

FIG.6

STEP 2-1 第2-1工程

12

転写フィルムへの 接着剤の塗布

COATING ADHESIVE TO TRANSFER FILM

5TEP 2-2 第2-2工程

一経時処理

TIME-BASED PROCESS

5TEP 2-3 第2-3王程

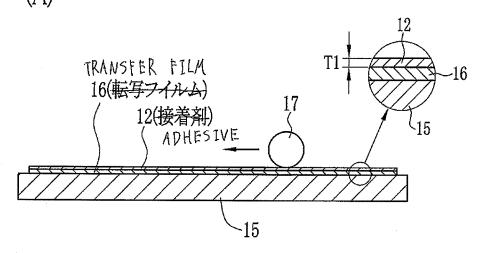
ガラス基板と転写 フイルムとの貼り合わせ APHERING GLASS SUBSTRATE AND TRANSFER FILM

STEP 24 第2-4工程

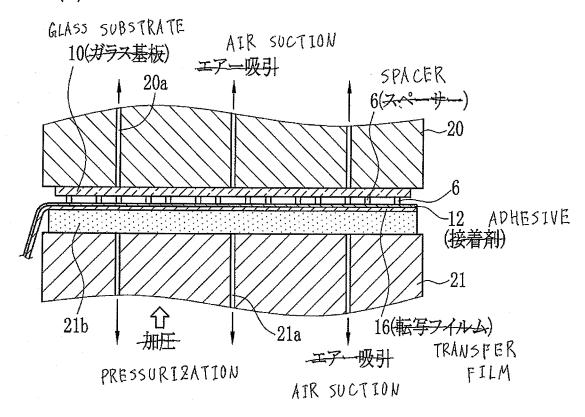
- 転写フィルムの剥離

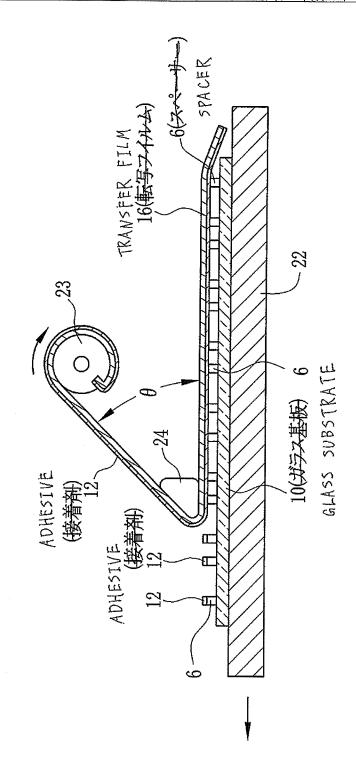
PEELING TRANSFER FILM 【<del>図</del>子】 PIG.¶

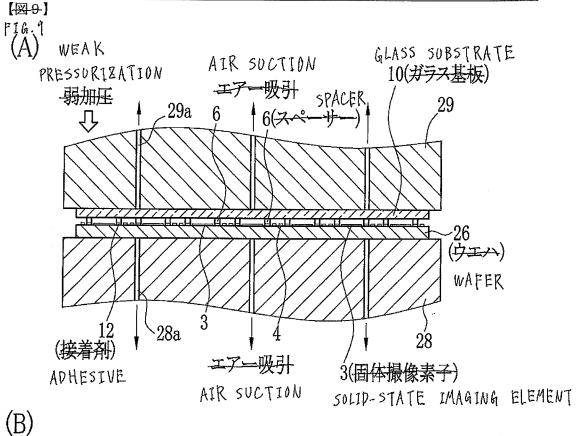
(A)



(B)







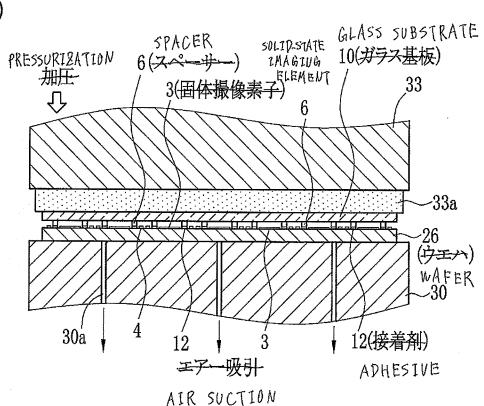
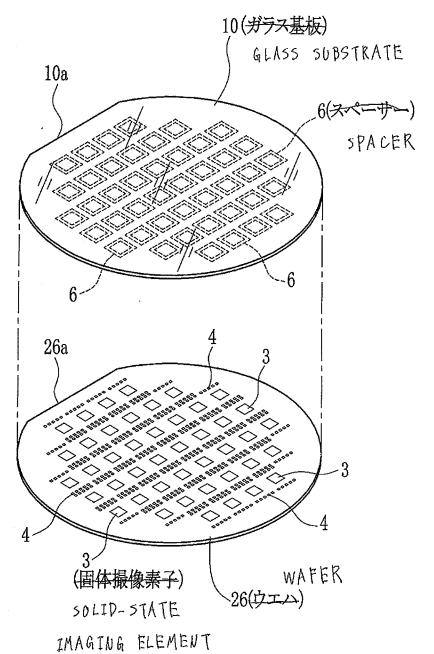


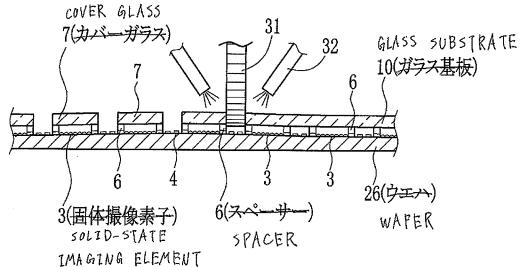
图1-0-

F16.10

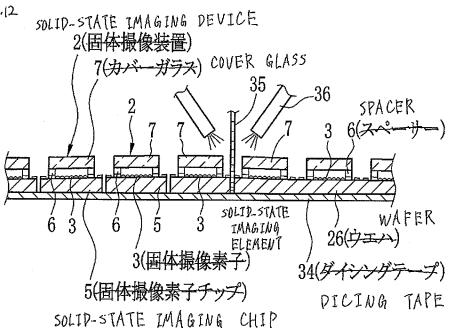


【图11】



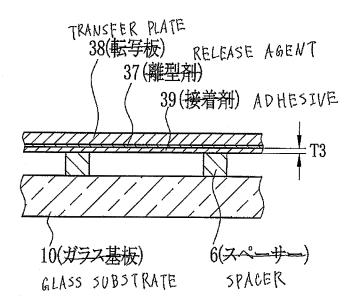


## 图1-2]

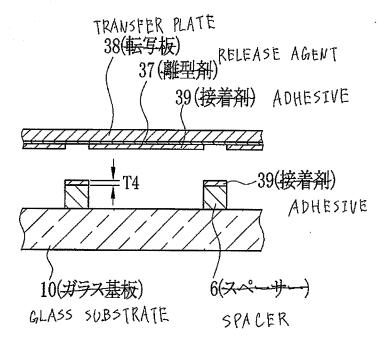


【图13】 FIG. B

(A)



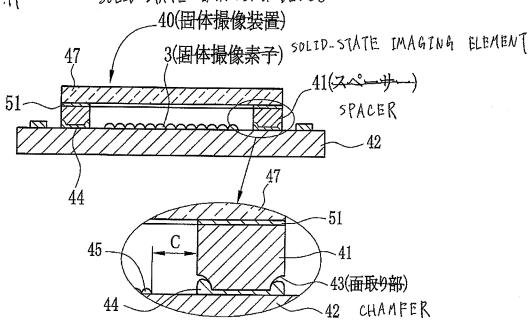
(B)



## 【図14】

FIG.14

SOLID-STATE IMAGING DEVICE



#### 图15]

FIG. 15

PIRST STEP 第1ステップ

・ガラス基板とスペーサ用 ウエハとの貼り合わせ ADHERING GLASS SUBSTRATE AND WAFER FOR SPACER

SECOND STEP 第2ステップ

ププ・レジストマスクの作成

FORMING RESIST MASK

THIRD STEP 第3ステップ

画取り部の形成 (等方性ドライエッチング) FORMING CHAMPERS
(ISOTOPIC DRY ETCHING)

FOURTH STEP 第42テップ

<del>スペーサーの形成</del> (異方性ドライエッチング) FORMING SPACERS

(ANISOTROPIC DRY ETCHING)

FIFTH STEP 第5ステップ

レジストマスク及び 接着剤の除去 REMOVING RESIST MASK AND ADHESIVE











